# IN THE U.S. PATENT AND TRADEMARK OFFICE

APPLICANTS:     **Michael R. Keenan**

SERIAL NO.:     Unknown                          GROUP NO.

FILED:          **February 4, 2004**              EXAMINER:

FOR:            **Spatial Compression Algorithms for the Analysis of Very Large Multivariate Images**

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

February 4, 2004

## INFORMATION DISCLOSURE STATEMENT

The following sections are being submitted for this Information Disclosure Statement:

1.  Preliminary Statements

    Applicants submit herewith patents, publications or other information of which they are aware, which they believe may be material to the examination of this application and in respect of which there may be a duty to disclose.

    The filing of this Information Disclosure Statement shall not be construed as a representation that a search has been made (37 CFR 1.97(g)), an admission that the information cited is, or is considered to be, material to patentability or that no other material information exists.

    The filing of this Information Disclosure Statement shall not be construed as an admission against interest in any manner. Notice of January 9, 1992, 1135 O.G. 13-25, at 25.

2.  Form PTO - 1449 (Modified).

3.  The person making this statement is the attorney or agent who signs below on the basis of the information supplied by the inventor(s) and the information in the attorney's or agent's file.

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Information Disclosure Statement
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**SD7213/S99838**
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## CERTIFICATE OF MAILING

I hereby certify that this paper (along with any referred to as being attached or enclosed) is being deposited with the U. S. Postal Service on the date shown below as Express Mail No. EV332388307US in an envelope addressed to the: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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_Martha Trujillo_
Martha Trujillo

| Form PTO-1449 (SNL-Modified) (2-91) | Atty Docket No: SD7213/S99838 |
|---|---|
| List of Patents and Publications for Applicant's | Serial Number: |
| Information Disclosure Statement | APPLICANT: Keenan |
| (use several sheets if necessary)   GROUP: | FILING DATE: February 4, 2004 |

## REFERENCE DESIGNATION

| Ex'r Init | Document No. | Date | U.S. Patent Documents Name / Foreign Patent Documents | Sub Class | Class | File Date / Translation |
|---|---|---|---|---|---|---|
| | Document No. | Date | Name | Class | Sub Class | Yes   \| X No |

|AA   | 6,584,413   6/24/2003   Keenan et al.

|AB   | 6,675,106   1/6/2004   Keenan et al

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| Examiner: | Date Considered: |
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